

# USE GAL DEVICES FOR NEW DESIGNS

FINAL

COM'L: H-15/25

## PALCE24V10H-15/25

Lattice Semiconductor

### EE CMOS 28-Pin Universal Programmable Array Logic

#### DISTINCTIVE CHARACTERISTICS

- Electrically erasable CMOS technology provides reconfigurable logic and full testability
- High speed CMOS technology
  - 15-ns propagation delay for “-15” version
  - 25-ns propagation delay for “-25” version
- Outputs individually programmable as registered or combinatorial
- Programmable output polarity
- Programmable enable/disable control
- Preloadable output registers for testability
- Automatic register reset on power-up
- Cost-effective 28-pin plastic SKINNYDIP and PLCC packages
- Extensive third-party support through FusionPLD partners
- Fully tested for 100% programming and functional yields and high reliability

#### GENERAL DESCRIPTION

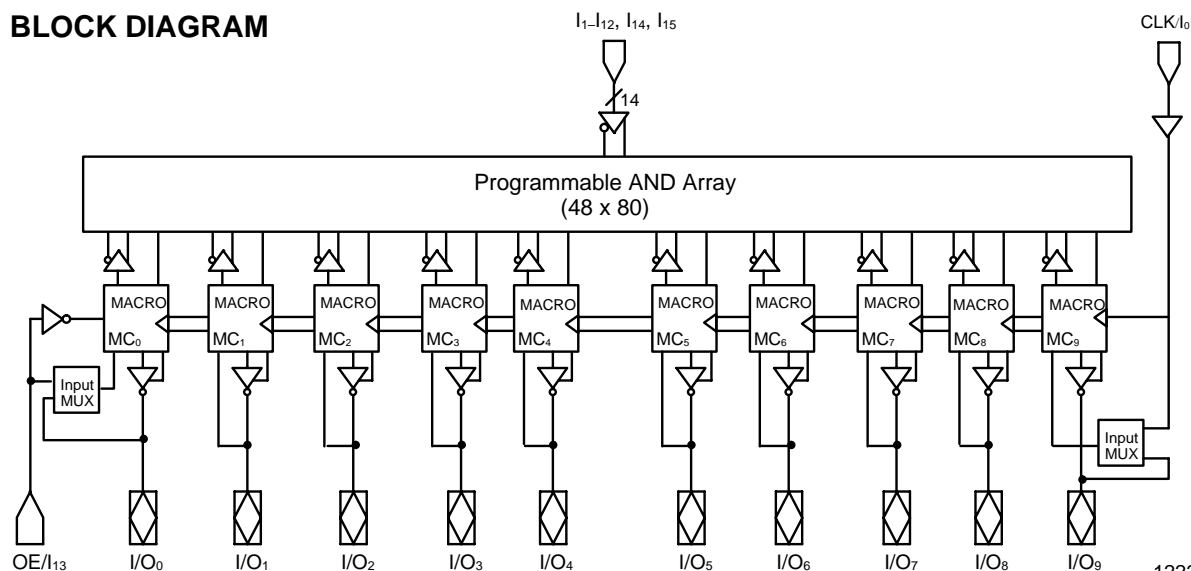
The PALCE24V10 is an advanced PAL device built with low-power, electrically-erasable CMOS technology. Its macrocells provide a universal device architecture.

The PALCE24V10 utilizes the familiar sum-of-products (AND/OR) architecture that allows users to implement complex logic functions easily and efficiently. Multiple levels of combinatorial logic can always be reduced to sum-of-products form, taking advantage of the very wide input gates available in PAL devices. The equations are programmed into the device through floating-gate cells in the AND logic array that can be erased electrically.

The fixed OR array allows up to eight product terms per output for logic functions. The sum of these products feeds the output macrocell. Each macrocell can be programmed as registered or combinatorial with an

active-high or active-low output. The output configuration is determined by two global bits and one local bit controlling four multiplexers in each macrocell.

#### BLOCK DIAGRAM

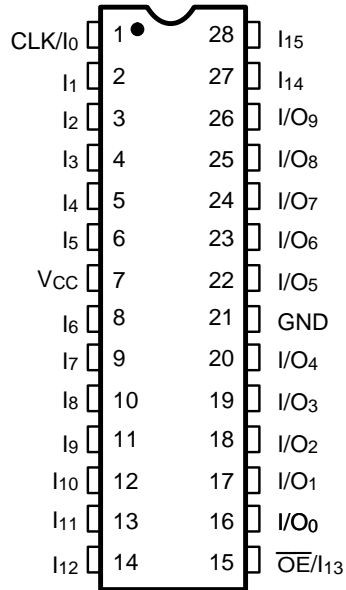


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# CONNECTION DIAGRAMS

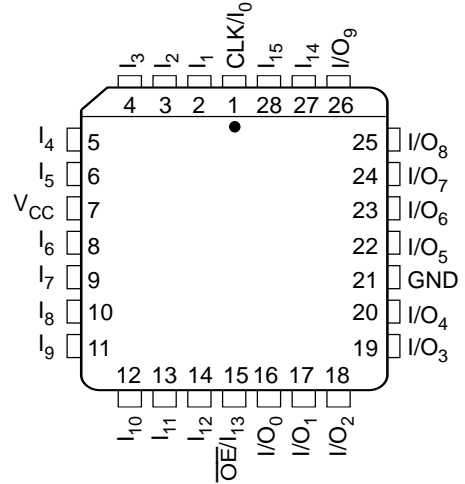
## Top View

**SKINNYDIP**



12222F-2

**PLCC**



12222F-3

**Note:**

Pin 1 is marked for orientation.

### PIN DESIGNATIONS

CLK = Clock

GND = Ground

I = Input

I/O = Input/Output

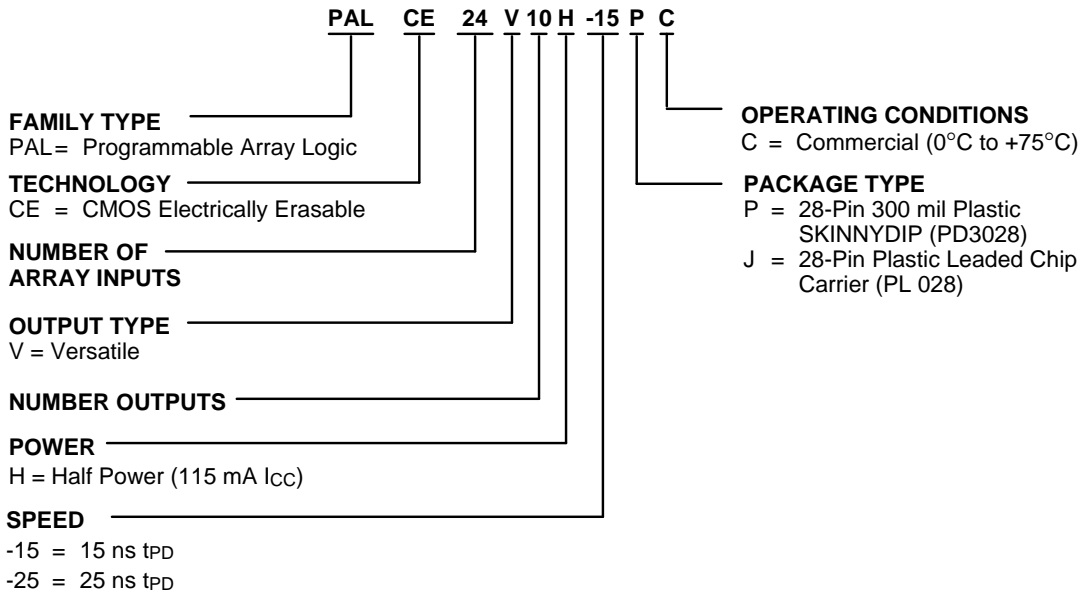
$\overline{\text{OE}}$  = Output Enable

V<sub>CC</sub> = Supply Voltage

# ORDERING INFORMATION

## Commercial Products

Programmable logic products for commercial applications are available with several ordering options. The order number (Valid Combination) is formed by a combination of:



Valid Combinations	
PALCE24V10H-15	PC, JC
PALCE24V10H-25	

### Valid Combinations

Valid Combinations lists configurations planned to be supported in volume for this device. Consult your local sales office to confirm availability of specific valid combinations and to check on newly released combinations.



## Configuration Options

Each macrocell can be configured as one of the following: registered output, combinatorial output, combinatorial I/O or dedicated input. In the registered output configuration, the output buffer is enabled by the  $\overline{OE}$  pin. In the combinatorial configuration, the buffer is either controlled by a product term or always enabled. In the dedicated input configuration, the buffer is always disabled.

The macrocell configurations are controlled by the configuration control word. It contains 2 global bits (SG0 and SG1) and 20 local bits (SL0<sub>0</sub> through SL0<sub>9</sub> and SL1<sub>0</sub> through SL1<sub>9</sub>). SG0 determines whether registers will be allowed. SG1 determines whether the output buffer is user-controlled or in a fixed state. Within each macrocell, SL0<sub>x</sub>, in conjunction with SG1, selects the configuration of the macrocell and SL1<sub>x</sub> sets the output as either active low or active high.

The configuration bits work by acting as control inputs for the multiplexers in the macrocell. There are four multiplexers: a product term input, an enable select, an output select, and a feedback select multiplexer. SG1 and SL0<sub>x</sub> are the control signals for all four multiplexers. In MC<sub>0</sub> and MC<sub>9</sub>,  $\overline{SG0}$  is added on the feedback multiplexer.

These configurations are summarized in table 1 and illustrated in figure 2.

If the PALCE24V10 is configured as a combinatorial device, the CLK and  $\overline{OE}$  pins are available as inputs to the array. If the device is configured with registers, the CLK and  $\overline{OE}$  pins cannot be used as data inputs.

### Registered Output Configuration

The control bit settings are SG0 = 0, SG1 = 1 and SL0<sub>x</sub> = 0. There is only one registered configuration. All eight product terms are available as inputs to the OR gate. Data polarity is determined by SL1<sub>x</sub>. SL1<sub>x</sub> is an input to the exclusive-OR gate which is the D input to the flip-flop. SL1<sub>x</sub> is programmed as 1 for inverted output or 0 for non-inverted output. The flip-flop is loaded on the LOW-to-HIGH transition of CLK. The feedback path is from  $\overline{Q}$  on the register. The output buffer is enabled by  $\overline{OE}$ .

### Combinatorial Configurations

The PALCE24V10 has three combinatorial output configurations: dedicated output in a non-registered device, I/O in a non-registered device and I/O in a registered device.

### Dedicated Output in a Non-Registered Device

The control settings are SG0 = 1, SG1 = 0, and SL0<sub>x</sub> = 0. All eight product terms are available to the OR gate. Because the macrocell is a dedicated output, the feedback is not used.

### Dedicated Input in a Non-Registered Device

The control bit settings are SG0 = 1, SG1 = 0 and SL0<sub>x</sub> = 1. The output buffer is disabled. The feedback signal is the I/O pin.

### Combinatorial I/O in a Non-Registered Device

The control settings are SG0 = 1, SG1 = 1, and SL0<sub>x</sub> = 1. Only seven product terms are available to the OR gate. The eighth product term is used to enable the output buffer. The signal at the I/O pin is fed back to the AND array via the feedback multiplexer. This allows the pin to be used as an input.

### Combinatorial I/O in a Registered Device

The control bit settings are SG0=0, SG1=1 and SL0<sub>x</sub> = 1. Only seven product terms are available to the OR gate. The eighth product term is used as the output enable. The feedback signal is the corresponding I/O signal.

Table 1. Macrocell Configurations

SG0	SG1	SL0 <sub>x</sub>	Cell Configuration
<b>Device has registers</b>			
0	1	0	Registered Output
0	1	1	Combinatorial I/O
<b>Device has no registers</b>			
1	0	0	Combinatorial Output
1	0	1	Dedicated Input
1	1	1	Combinatorial I/O

### Programmable Output Polarity

The polarity of each macrocell output can be active high or active low, either to match output signal needs or to reduce product terms. Programmable polarity allows Boolean expressions to be written in their most compact form (true or inverted), and the output can still be of the desired polarity. It can also save "DeMorganizing" efforts.

Selection is made through a programmable bit SL1<sub>x</sub> which controls an exclusive-OR gate at the output of the AND/OR logic. The output is active high if SL1<sub>x</sub> is a 0 and active low if SL1<sub>x</sub> is a 1.

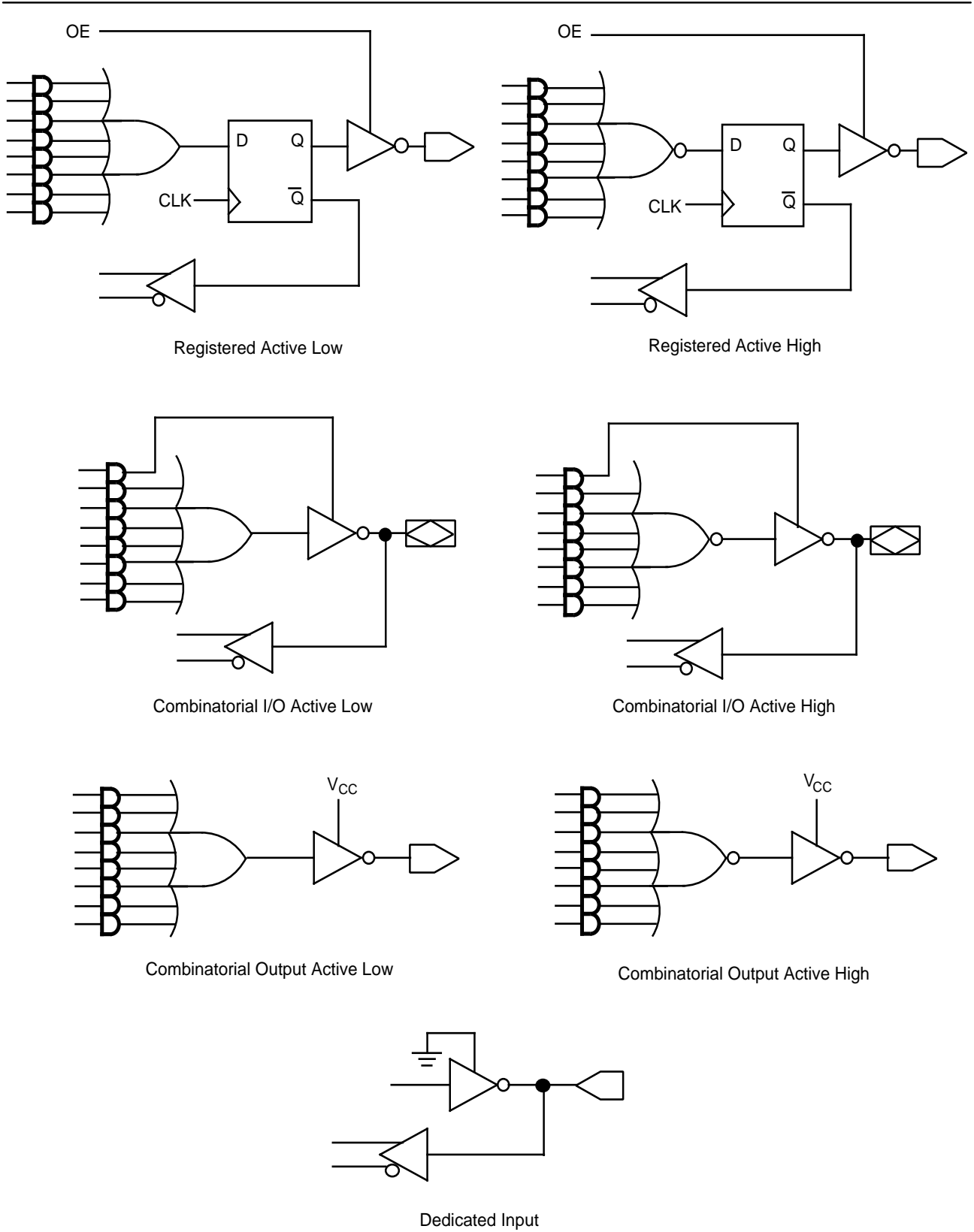


Figure 2. Macrocell Configurations

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## Power-Up Reset

All flip-flops power up to a logic LOW for predictable system initialization. Outputs of the PALCE24V10 depend on whether they are selected as registered or combinatorial. If registered is selected, the output will be HIGH. If combinatorial is selected, the output will be a function of the logic.

## Register Preload

The register on the PALCE24V10 Series can be preloaded from the output pins to facilitate functional testing of complex state machine designs. This feature allows direct loading of arbitrary states, making it unnecessary to cycle through long test vector sequences to reach a desired state. In addition, transitions from illegal states can be verified by loading illegal states and observing proper recovery.

## Security Bit

A security bit is provided on the PALCE24V10 as a deterrent to unauthorized copying of the array configuration patterns. Once programmed, this bit defeats readback of the programmed pattern by a device programmer, securing proprietary designs from competitors. However, programming and verification are also defeated by the security bit. The bit can only be erased in conjunction with the array during an erase cycle.

## Electronic Signature Word

An electronic signature word is provided in the PALCE24V10. It consists of 64 bits of programmable memory that can contain any user-defined data. The signature data is always available to the user independent of the security bit.

## Programming and Erasing

The PALCE24V10 can be programmed on standard logic programmers. It also may be erased to reset a previously configured device back to its virgin state. Erasure is automatically performed by the programming hardware. No special erase operation is required.

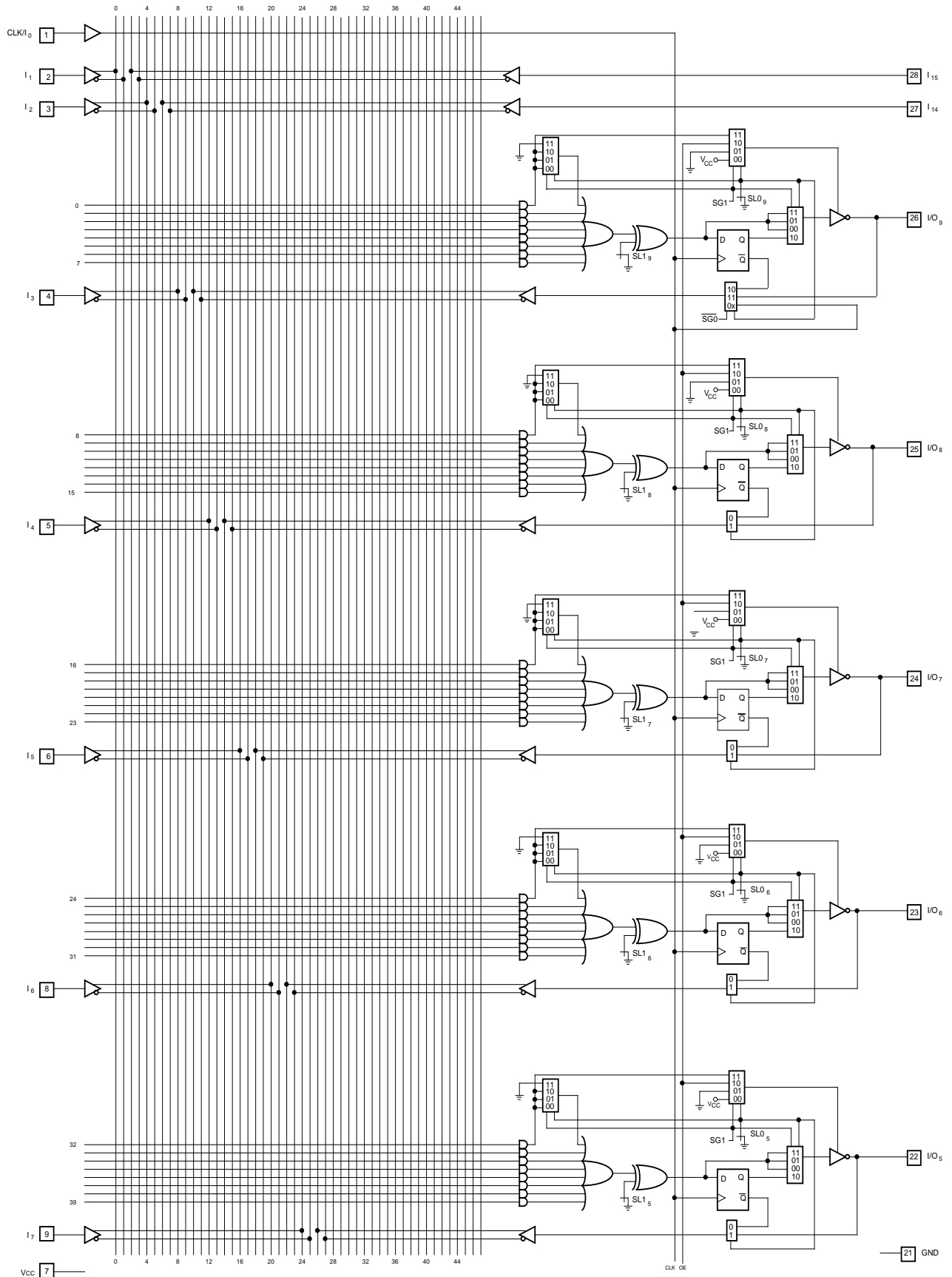
## Quality and Testability

The PALCE24V10 offers a very high level of built-in quality. The erasability of the device provides a direct means of verifying performance of all the AC and DC parameters. In addition, it verifies complete programmability and functionality of this device to yield the highest programming yields and post-programming function yields in the industry.

## Technology

The PALCE24V10 is fabricated with our advanced electrically-erasable (EE) CMOS process. The array connections are formed with proven EE cells. Inputs and outputs are designed to be compatible with TTL devices. This technology provides strong input-clamp diodes, output slew-rate control, and a grounded substrate for clean switching.

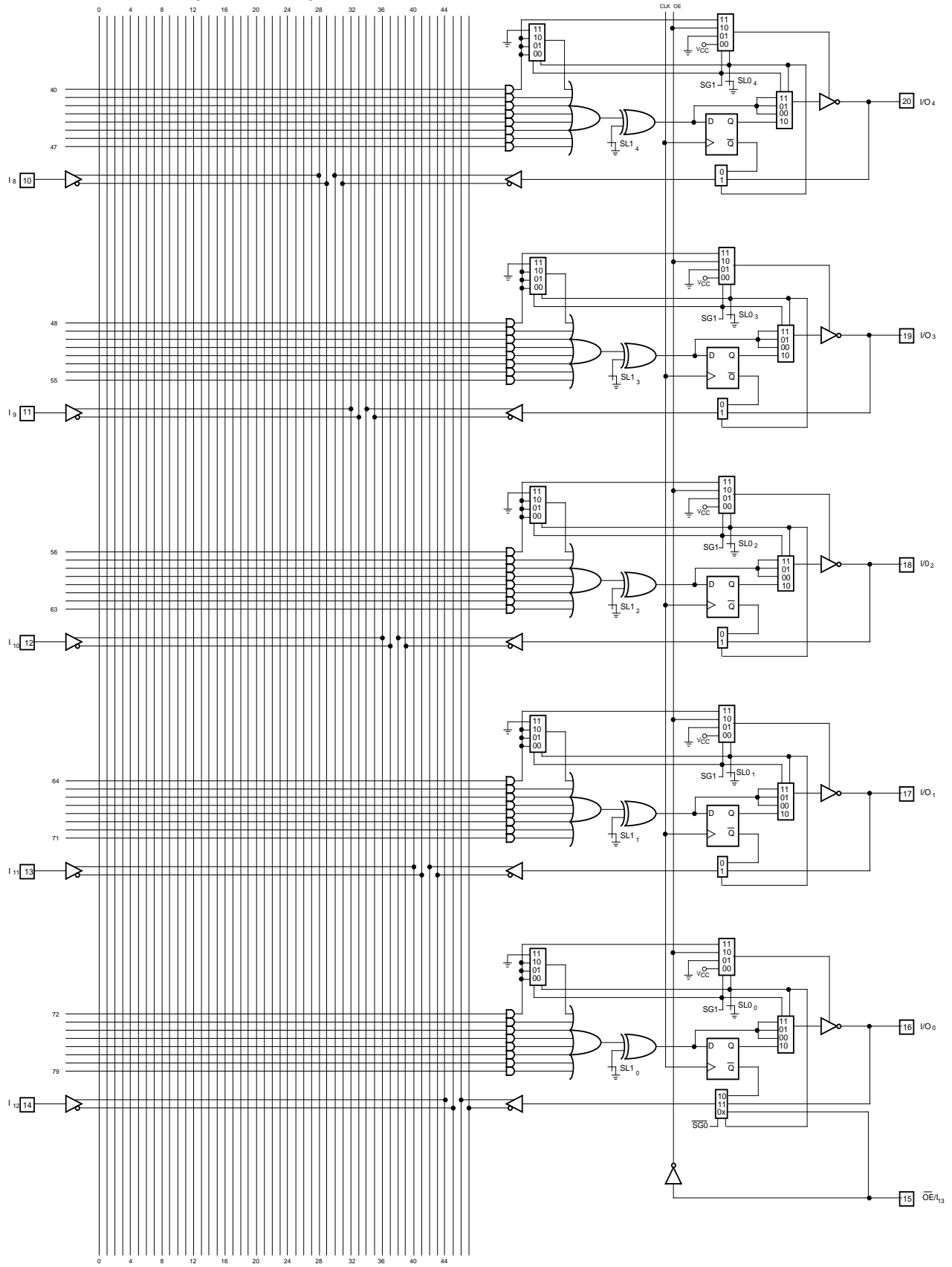
# LOGIC DIAGRAM



12222F-6



# LOGIC DIAGRAM (continued)



12222F-6  
(concluded)

## ABSOLUTE MAXIMUM RATINGS

Storage Temperature	−65°C to +150°C
Ambient Temperature with Power Applied	−55°C to +125°C
Supply Voltage with Respect to Ground	−0.5 V to +7.0 V
DC Input Voltage	−0.5 V to $V_{CC} + 0.5$ V
DC Output or I/O Pin Voltage	−0.5 V to $V_{CC} + 0.5$ V
Static Discharge Voltage	2001 V
Latchup Current ( $T_A = 0^\circ\text{C}$ to $+75^\circ\text{C}$ )	100 mA

Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to Absolute Maximum Ratings for extended periods may affect device reliability. Programming conditions may differ.

## OPERATING RANGES

### Commercial (C) Devices

Temperature ( $T_A$ ) Operating in Free Air	0°C to +75°C
Supply Voltage ( $V_{CC}$ ) with Respect to Ground	+4.75 V to +5.25 V

Operating ranges define those limits between which the functionality of the device is guaranteed.

## DC CHARACTERISTICS over COMMERCIAL operating ranges unless otherwise specified

Parameter Symbol	Parameter Description	Test Conditions	Min	Max	Unit
$V_{OH}$	Output HIGH Voltage	$I_{OH} = -3.2$ mA $V_{IN} = V_{IH}$ or $V_{IL}$ $V_{CC} = \text{Min}$	2.4		V
$V_{OL}$	Output LOW Voltage	$I_{OL} = 24$ mA $V_{IN} = V_{IH}$ or $V_{IL}$ $V_{CC} = \text{Min}$		0.5	V
$V_{IH}$	Input HIGH Voltage	Guaranteed Input Logical HIGH Voltage for all Inputs (Note 1)	2.0		V
$V_{IL}$	Input LOW Voltage	Guaranteed Input Logical LOW Voltage for all Inputs (Note 1)		0.8	V
$I_{IH}$	Input HIGH Leakage Current	$V_{IN} = 5.25$ V, $V_{CC} = \text{Max}$ (Note 2)		10	$\mu\text{A}$
$I_{IL}$	Input LOW Leakage Current	$V_{IN} = 0$ V, $V_{CC} = \text{Max}$ (Note 2)		-10	$\mu\text{A}$
$I_{OZH}$	Off-State Output Leakage Current HIGH	$V_{OUT} = 5.25$ V, $V_{CC} = \text{Max}$ $V_{IN} = V_{IH}$ or $V_{IL}$ (Note 2)		10	$\mu\text{A}$
$I_{OZL}$	Off-State Output Leakage Current LOW	$V_{OUT} = 0$ V, $V_{CC} = \text{Max}$ $V_{IN} = V_{IH}$ or $V_{IL}$ (Note 2)		-10	$\mu\text{A}$
$I_{SC}$	Output Short-Circuit Current	$V_{CC} = \text{Max}$ $V_{OUT} = 0.5$ V (Note 3)	-30	-150	mA
$I_{CC}$	Supply Current	Outputs Open ( $I_{OUT} = 0$ mA) $V_{CC} = \text{Max}$ , $f = 15$ MHz		115	mA

### Notes:

1. These are absolute values with respect to device ground and all overshoots due to system and/or tester noise are included.
2. I/O pin leakage is the worst case of  $I_{IL}$  and  $I_{OZL}$  (or  $I_{IH}$  and  $I_{OZH}$ ).
3. Not more than one output should be shorted at a time and duration of the short-circuit should not exceed one second.  $V_{OUT} = 0.5$  V has been chosen to avoid test problems caused by tester ground degradation.

## CAPACITANCE (Note 1)

Parameter Symbol	Parameter Descriptions	Test Conditions		Typ	Unit
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 2.0 V	V <sub>CC</sub> = 5.0 V, T <sub>A</sub> = 25°C,	5	pF
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 2.0 V	f = 1 MHz	8	pF

**Note:**

1. These parameters are not 100% tested, but are evaluated at initial characterization and at any time the design is modified where capacitance may be affected.

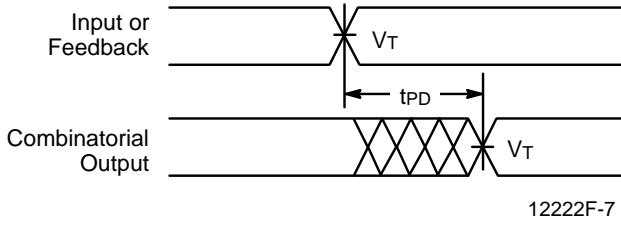
## SWITCHING CHARACTERISTICS over COMMERCIAL operating ranges (Note 2)

Parameter Symbol	Parameter Description		-15		-25		Unit
			Min	Max	Min	Max	
t <sub>PD</sub>	Input or Feedback to Combinatorial Output			15		25	ns
t <sub>S</sub>	Setup Time from Input or Feedback to Clock			10		12	ns
t <sub>H</sub>	Hold Time		0		0		ns
t <sub>CO</sub>	Clock to Output			10		12	ns
t <sub>WL</sub>	Clock Width	LOW	6		8		ns
t <sub>WH</sub>		HIGH	6		8		ns
f <sub>MAX</sub>	Maximum Frequency (Notes 3 and 4)	External Feedback	1/(t <sub>S</sub> + t <sub>CO</sub> )	50		41.6	MHz
		Internal Feedback (f <sub>CNT</sub> )	1/(t <sub>S</sub> + t <sub>CF</sub> )	66		50	MHz
		No Feedback	1/(t <sub>WH</sub> + t <sub>WL</sub> )	83.3		62.5	MHz
t <sub>PZX</sub>	$\overline{OE}$ to Output Enable (Note 3)			15		20	ns
t <sub>PXZ</sub>	$\overline{OE}$ to Output Disable (Note 3)			15		20	ns
t <sub>EA</sub>	Input to Output Enable Using Product Term Control (Note 3)			15		25	ns
t <sub>ER</sub>	Input to Output Disable Using Product Term Control (Note 3)			15		25	ns

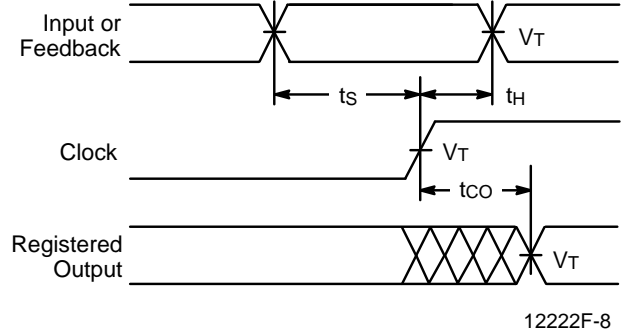
**Notes:**

2. See Switching Test Circuit for test conditions.
3. These parameters are not 100% tested, but are evaluated at initial characterization and at any time the design is modified where frequency may be affected.
4. t<sub>CF</sub> is a calculated value and is not guaranteed. t<sub>CF</sub> can be found using the following equation:  
 $t_{CF} = 1/f_{MAX} \text{ (internal feedback)} - t_S$

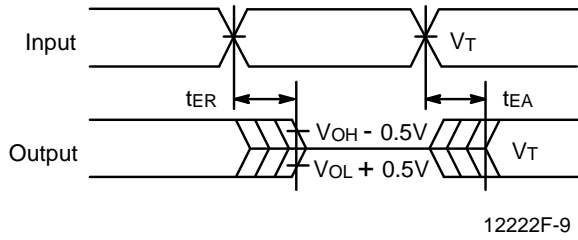
## SWITCHING WAVEFORMS



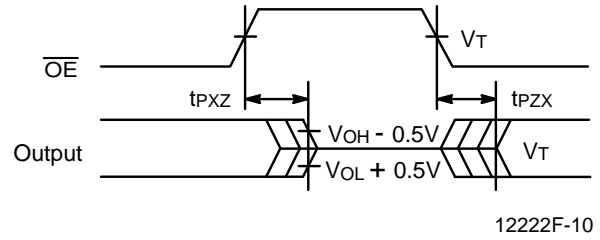
**Combinatorial Output**



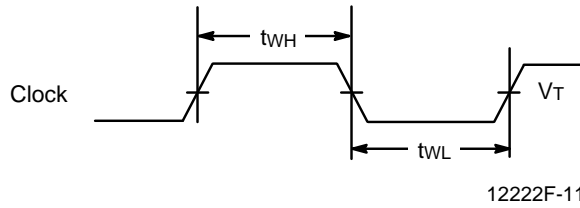
**Registered Output**



**Input to Output Disable/Enable**



**$\overline{OE}$  to Output Disable/Enable**




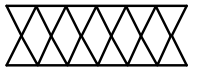
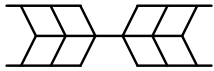


**Clock Width**

**Notes:**

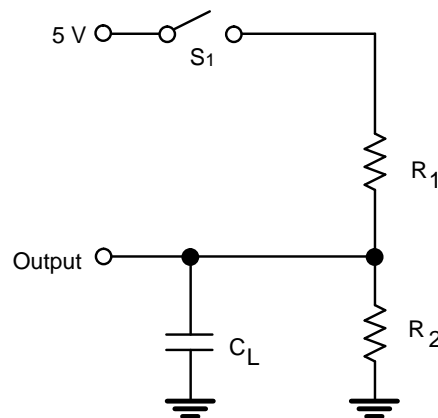
1.  $V_T = 1.5\text{ V}$
2. Input pulse amplitude 0 V to 3.0 V.
3. Input rise and fall times 2 ns–5 ns typical.

## KEY TO SWITCHING WAVEFORMS

WAVEFORM	INPUTS	OUTPUTS
	Must be Steady	Will be Steady
	May Change from H to L	Will be Changing from H to L
	May Change from L to H	Will be Changing from L to H
	Don't Care, Any Change Permitted	Changing, State Unknown
	Does Not Apply	Center Line is High-Impedance "Off" State

KS000010-PAL

## SWITCHING TEST CIRCUIT



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Specification	S <sub>1</sub>	C <sub>L</sub>	R <sub>1</sub>	R <sub>2</sub>	Measured Output Value
t <sub>PD</sub> , t <sub>CO</sub>	Closed	50 pF	200 Ω	390 Ω	1.5 V
t <sub>PZX</sub> , t <sub>EA</sub>	Z → H: Open Z → L: Closed				1.5 V
t <sub>PXZ</sub> , t <sub>ER</sub>	H → Z: Open L → Z: Closed	5 pF			H → Z: V <sub>OH</sub> - 0.5 V L → Z: V <sub>OL</sub> + 0.5 V

## ENDURANCE CHARACTERISTICS

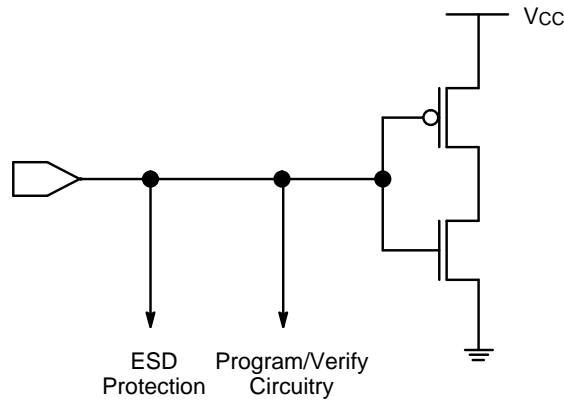
The PALCE24V10 is manufactured using our advanced electrically erasable process. This technology uses an EE cell to replace the fuse link used in bipolar

parts. As a result, the device can be erased and reprogrammed—a feature which allows 100% testing at the factory.

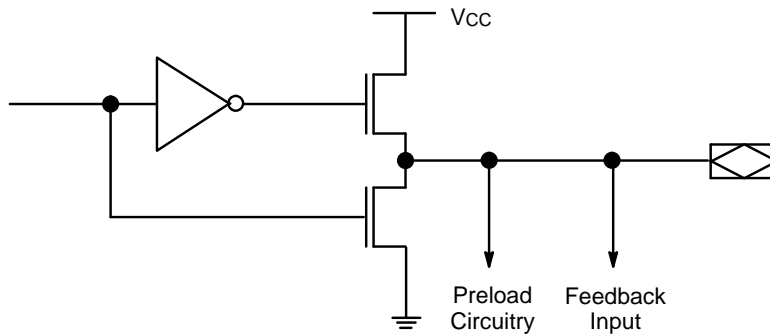
### Endurance Characteristics

Symbol	Parameter	Test Conditions	Min	Unit
tDR	Min Pattern Data Retention Time	Max Storage Temperature	10	Years
		Max Operating Temperature	20	Years
N	Min Reprogramming Cycles	Normal Programming Conditions	100	Cycles

## INPUT/OUTPUT EQUIVALENT SCHEMATICS



Typical Input



Typical Output

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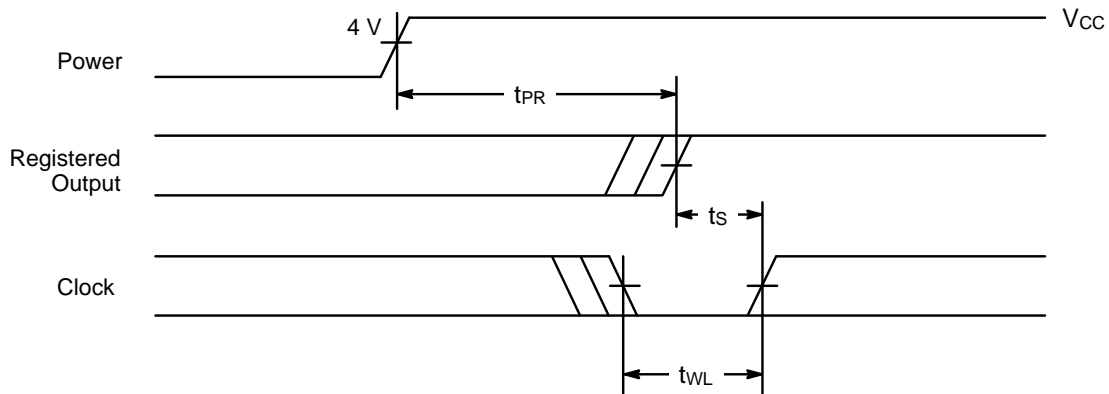
## POWER-UP RESET

The PALCE24V10 has been designed with the capability to reset during system power-up. Following power-up, all flip-flops will be reset to LOW. The output state will be HIGH independent of the logic polarity. This feature provides extra flexibility to the designer and is especially valuable in simplifying state machine initialization. A timing diagram and parameter table are shown below.

Due to the synchronous operation of the power-up reset and the wide range of ways  $V_{CC}$  can rise to its steady state, two conditions are required to ensure a valid power-up reset. These conditions are:

- The  $V_{CC}$  rise must be monotonic.
- Following reset, the clock input must not be driven from LOW to HIGH until all applicable input and feedback setup times are met.

Parameter Symbol	Parameter Description	Min	Max	Unit
$t_{PR}$	Power-Up Reset Time		1000	ns
$t_s$	Input or Feedback Setup Time	See Switching Characteristics		
$t_{WL}$	Clock Width LOW			



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Power-Up Reset Waveform